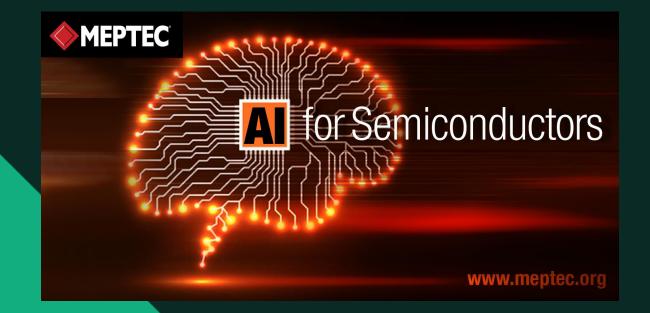


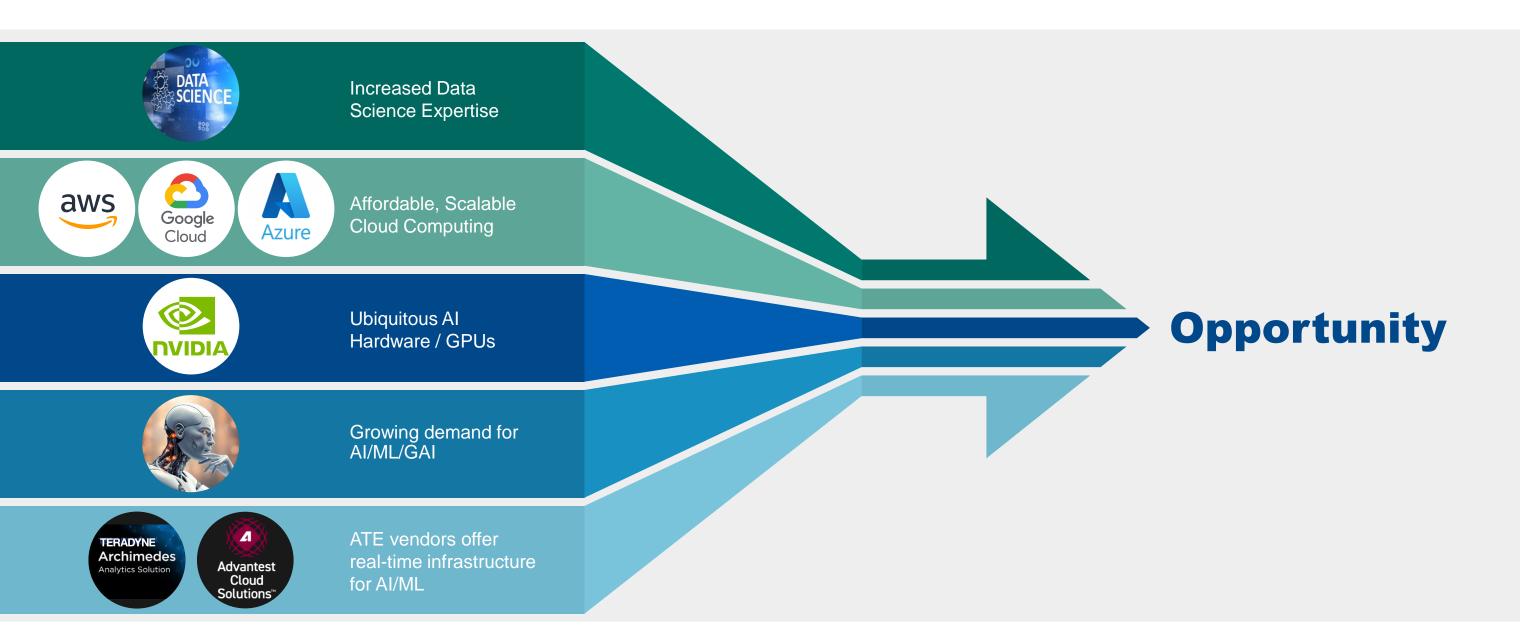
# **Implementing Real-time Al in High-Volume Test**

Michael Schuldenfrei, NI Fellow Michael.Schuldenfrei@ni.com



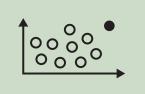


# **Converging Trends Creating an Opportunity**





# **Edge (and Cloud) AI Examples**



Outlier detection (Advanced)



Escape prevention (Equipment Health etc.)



Optical defect detection / ROI quality (e.g., welds, soldering etc.)



RMA reduction / prediction



Parametric trend detection



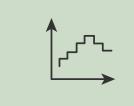
Parametric insights



Scratch detection (wafers)



Al based RCA



Waveform anomaly detection



Battery analytics (capacity, smart pairing, etc.)



Process optimization (e.g., Adaptive manufacturing)



Early failure detection



Next operation reduction



Monitoring and auto RCA (UPH, cycle time, yield, error code distributions etc.)



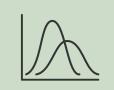
Process variation detection



Yield trend detection



Wafer classification



Equipment utilization/variations



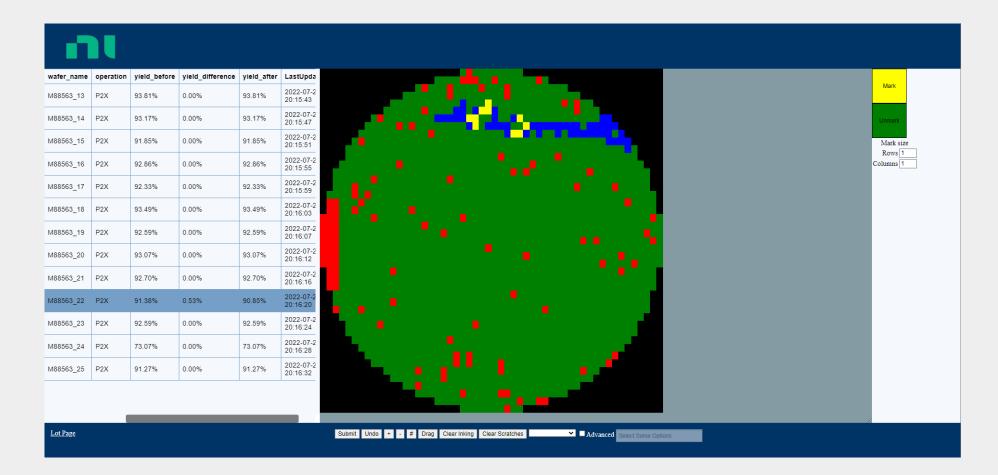
Predictive / JIT maintenance



Test (program) comparison



## **Scratch Detection**



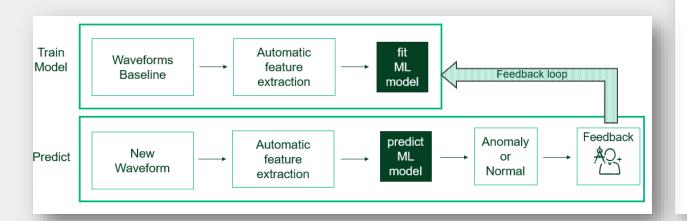
- Uses deep learning (DL)
   algorithms to detect scratches
- Automatically suggests inking scraps suspect dies around the scratch
- Improves over time given user feedback



# **Preventative Maintenance Using Waveforms**

### AI-based alerting on anomalies

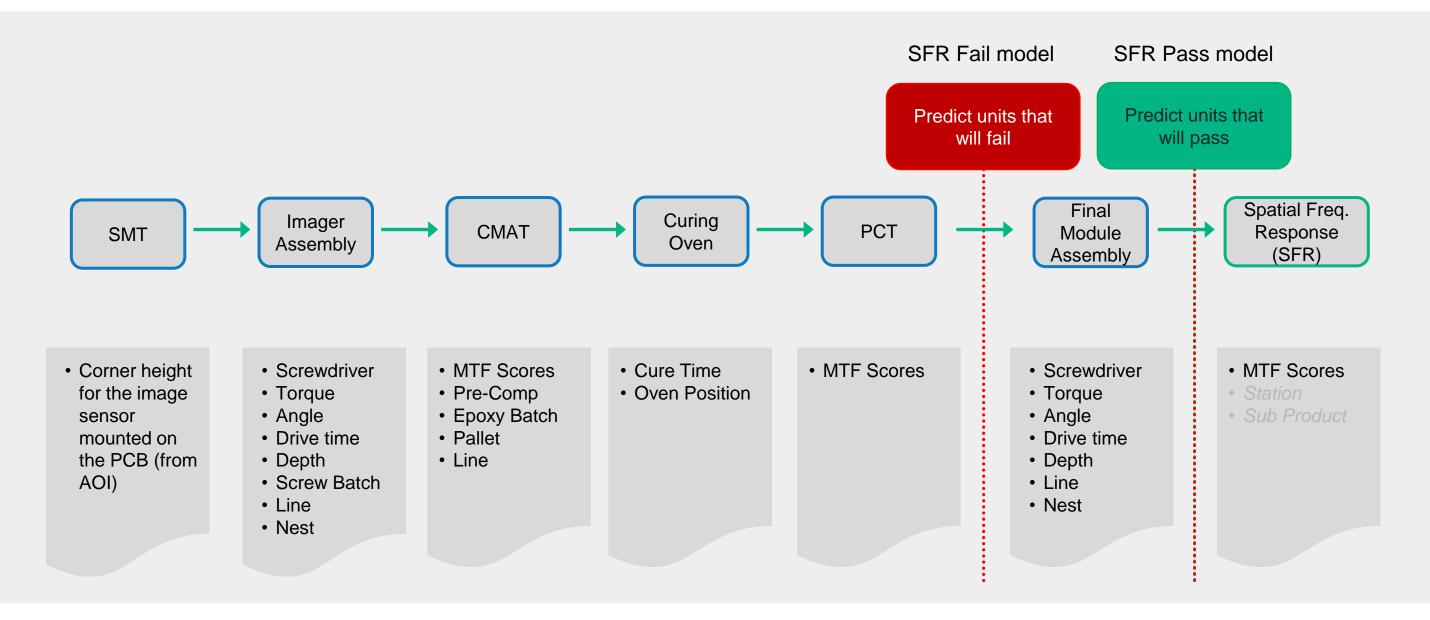
- Multivariate
   Holistic view of the waveform
- Minimal configuration
   Automatic identification
   and extraction of relevant features
- Feedback loop
   Improves with user feedback



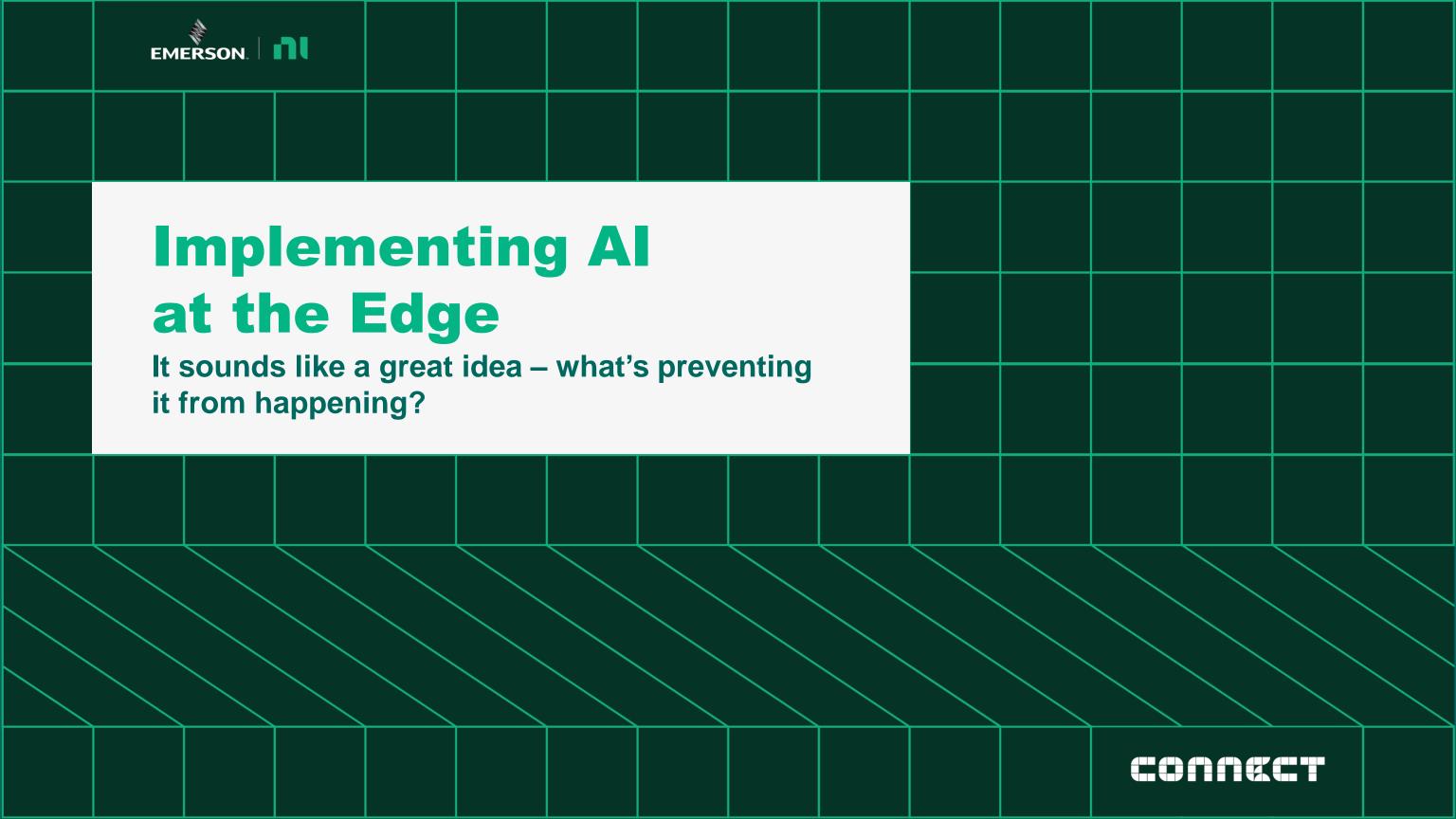




# **Next Operation Optimization / Lean Coverage**







# The Full Machine Learning Lifecycle

Train a model Deploy and act Learn Act upon the model with data and evaluate business value **Understand** Monitor data and Validate Adapt changes and model update performance to model/process identify changes



# **ML Challenges**



#### Learn

- Getting data
   Data scientists waste time getting and organizing data
- Feature extraction
   It is difficult to extract complex features from the data set
- Freedom of choice
   Data scientists want to
   use their favorite tools
   and the latest-and greatest algorithms

#### Act

- Complex "plumbing"
   Data scientists waste time dealing with the "plumbing" associated with getting a model into production
- Actionability

   Taking action requires
   integration with
   equipment and systems
- Distributed mfg.
   Issues compounded in distributed, outsourced mfg.

#### Validate

- Ongoing validation
   Production models
   need to be validated all
   the time
- Ongoing data collection Data collection becomes an ongoing concern
- Technical debt
   Data scientists end up spending time monitoring "old" projects instead of investing in new ones

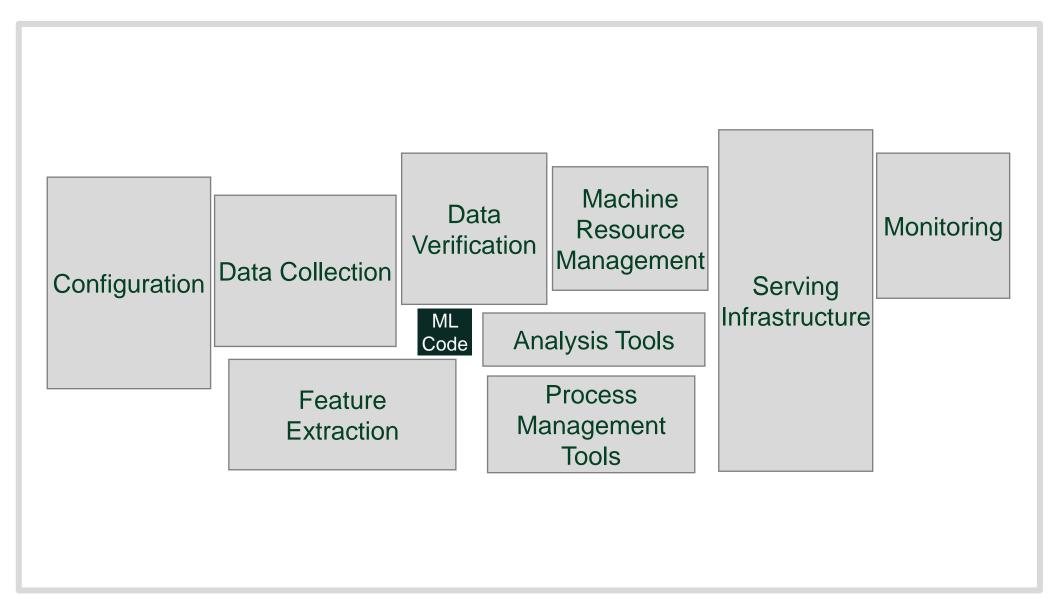
### Adapt

- Stale models
   Production changes inevitably cause models to go stale
- Human-in-the-loop
   Users need to review
   the results of a model
   and provide feedback
   to fine-tune it
- Relearning
   Model relearning is
   often manual



# **Hidden Complexity – the Google View**

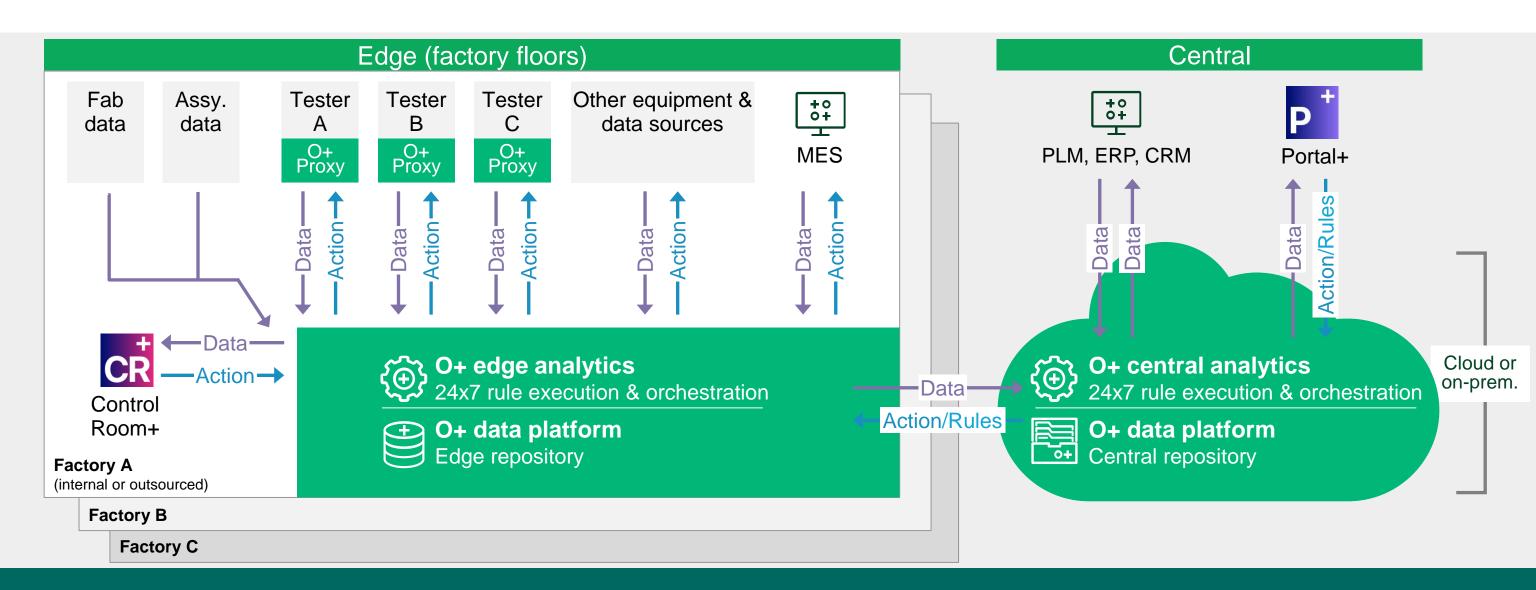
It's all about the infrastructure



Source: Google article from 2014: Hidden Technical Debt in Machine Learning Systems https://papers.nips.cc/paper/5656-hidden-technical-debt-in-machine-learning-systems.pdf



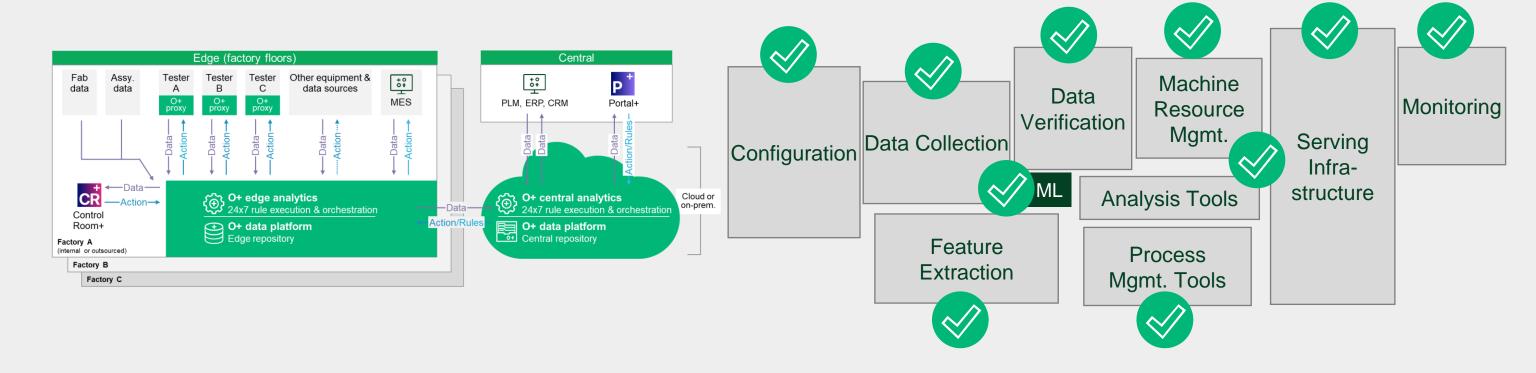
# Global Operations – "GO" – Architecture



Actionable insights across all manufacturing and test processes



# **Optimal+ GO – Comprehensive ML Operations**

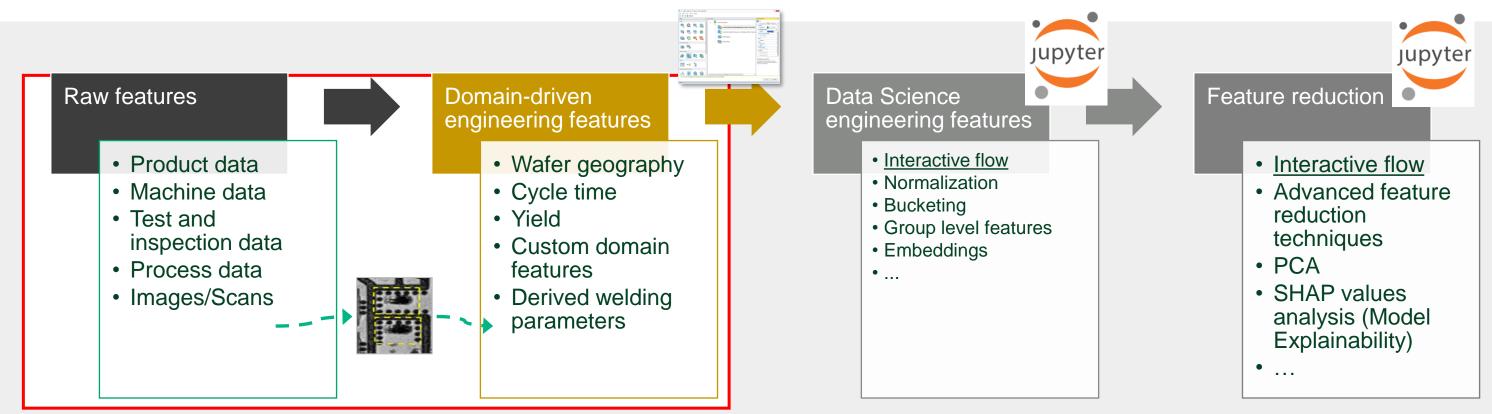


Optimal+ covers the full scope all the way through ML deployment



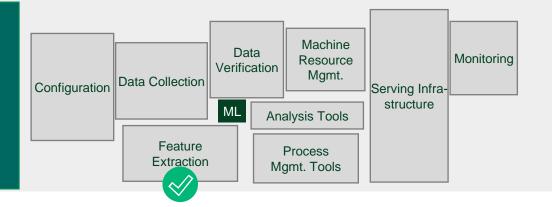
### **Feature Extraction**





Engineering features benefit ML models but require domain expertise.

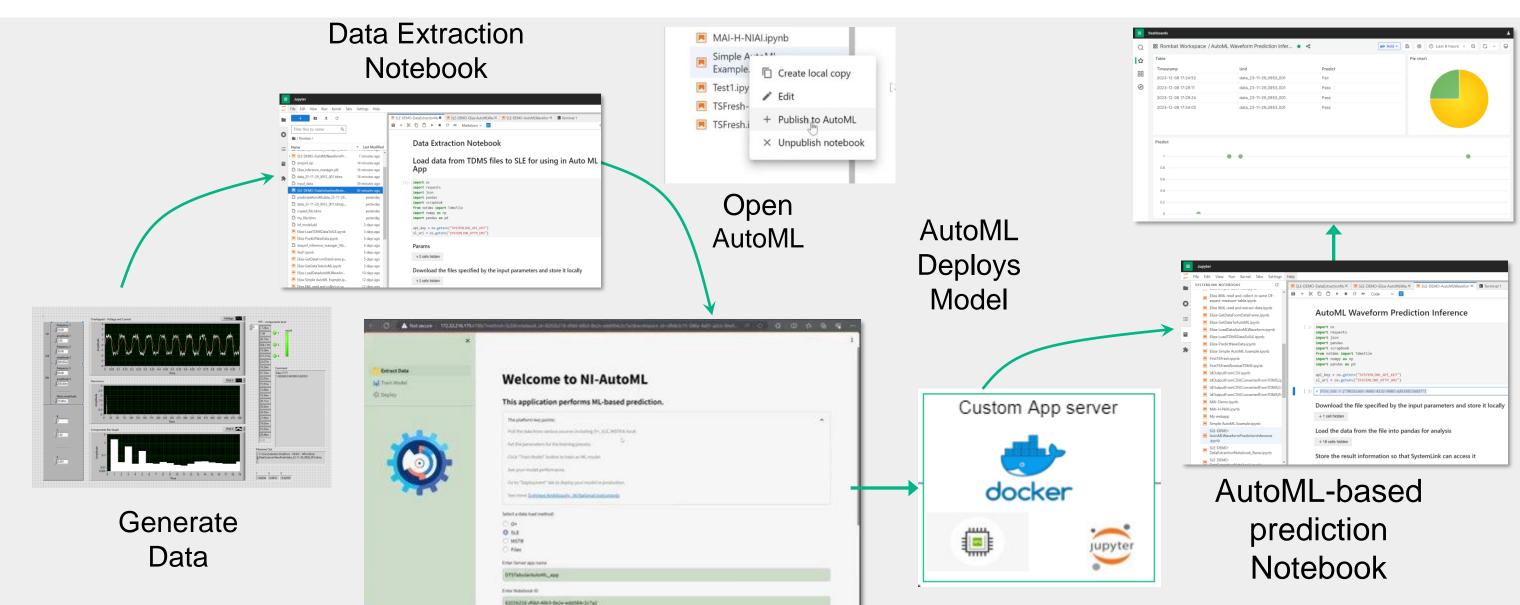
The platform saves time by contextualizing data into ML-ready datasets and calculating domain-specific features.





### **AutoML**

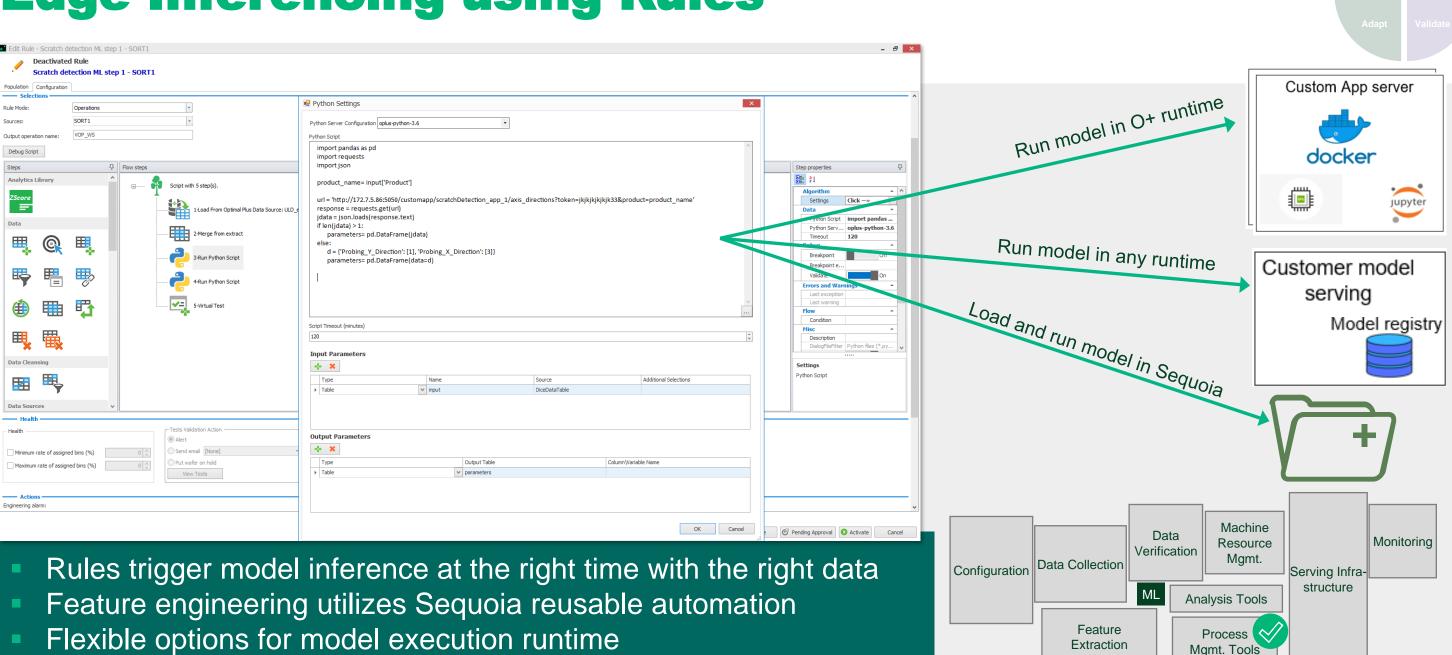




**AutoML Train Models** 



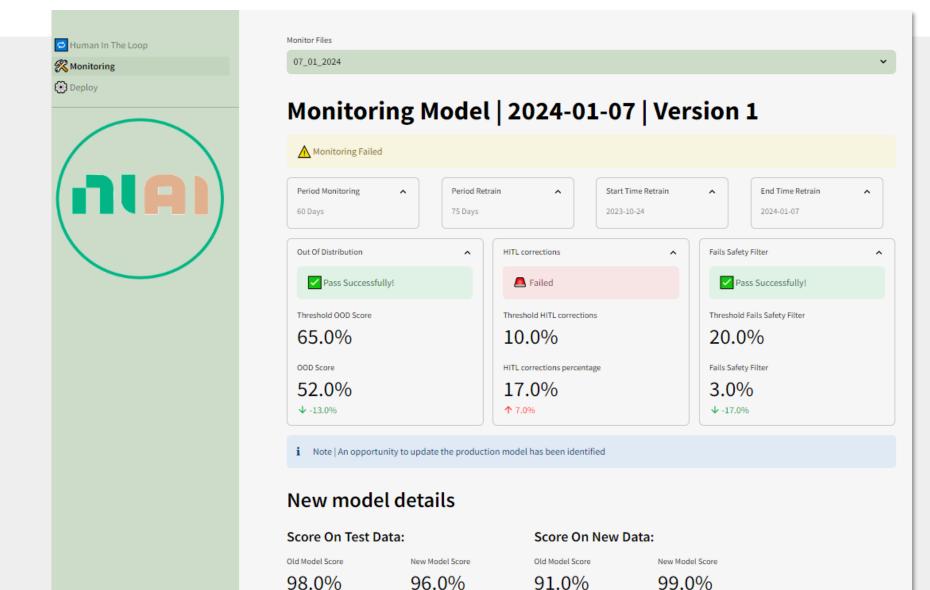
# **Edge Inferencing using Rules**



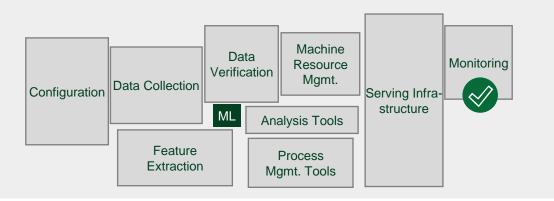


# Monitoring an AutoML App





- Automatically identify deteriorating model results
- Relearn on latest data to improve model





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Replace The Production Model

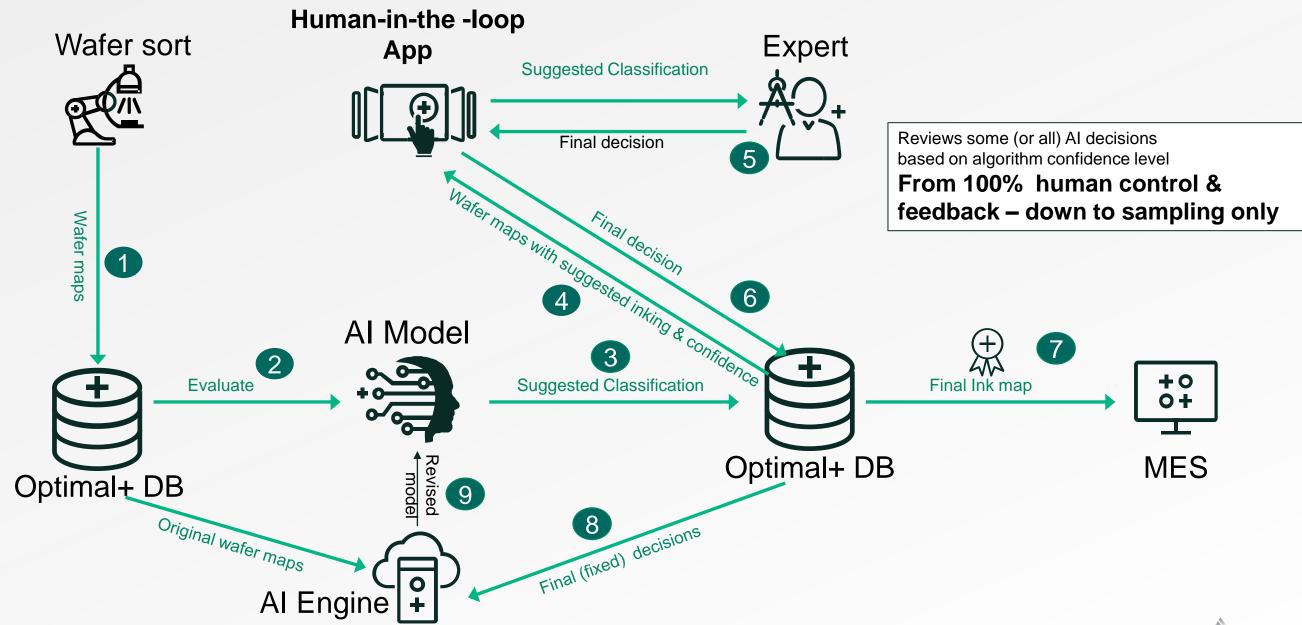
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# **Human-in-the-Loop**

Improve model while gaining user confidence







# The Full Machine Learning Lifecycle



#### Learn

- Getting data
   Data is collected and harmonized all the time, making it available at the click of a button
- Feature extraction
   Advanced features
   are extracted via out of-the-box capabilities
   (e.g. geographic and
   parametric outliers)
- Freedom of choice
   Full support for data
   science platforms

#### Act

- Complex "plumbing"
   Plumbing is handled under the hood by the Optimal+ infrastructure
- Actionability
   Integration with equipment and systems is part of the Optimal+ deployment
- Distributed mfg.
   Optimal+ is deployed across the entire mfg. ecosystem internal and outsourced

#### Validate

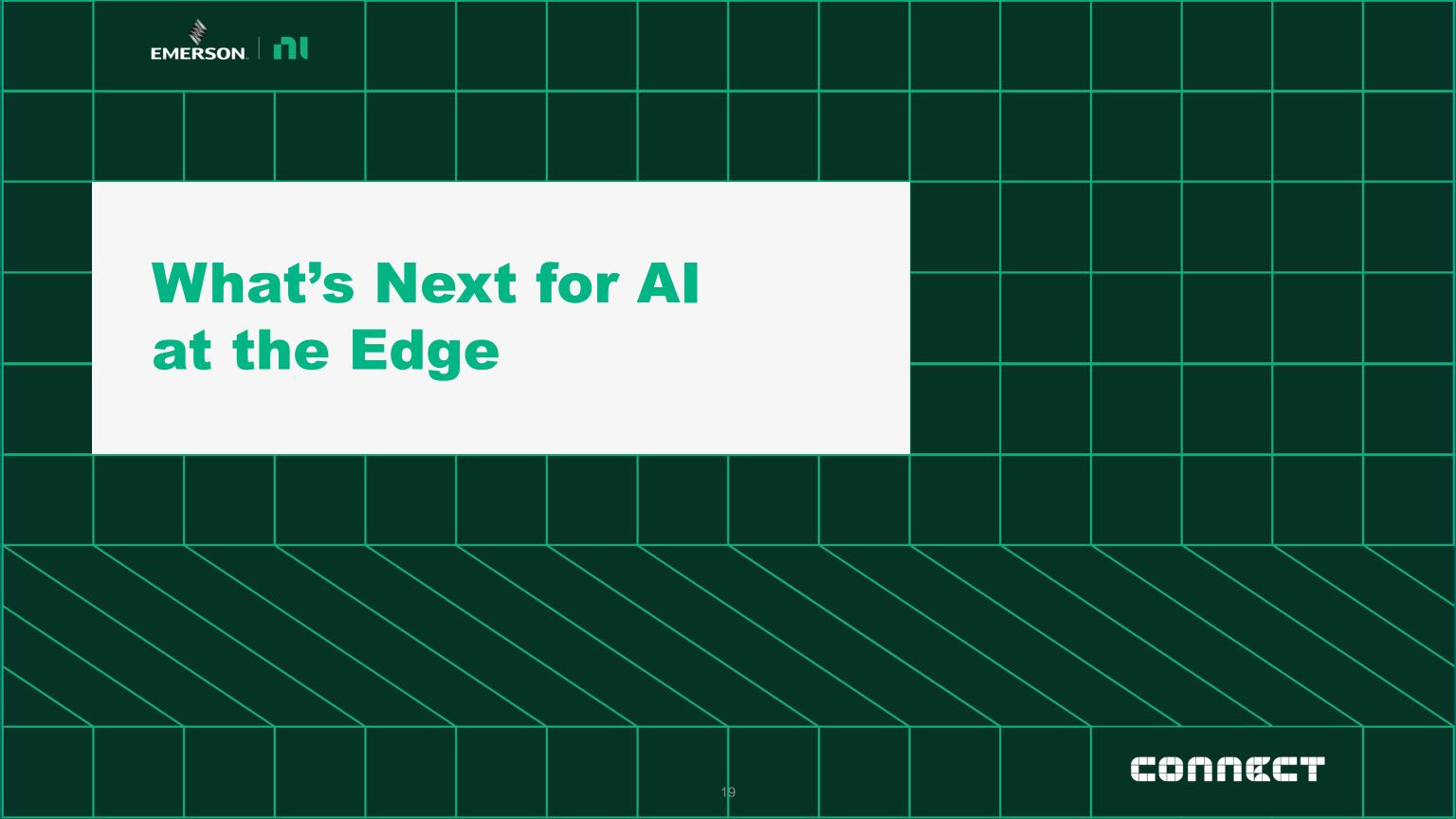
- Ongoing validation
   Standard rules
   monitor ML models
   for excursions
- Ongoing data collection

  Data collection and harmonization is already fully automatic
- Technical debt
   24x7 monitoring frees
   data scientists for
   their next project

### Adapt

- Stale models
   Automated rules
   detect when models
   are going stale and
   can even disable
   them if needed
- Human-in-the-loop
   Users can browse
   results and provide
   feedback directly
- Relearning
   Model relearning can
   be partially or fully
   automated





### NI Global Operations

### Real-time Application Enablement Layer (DIY & Canned models)



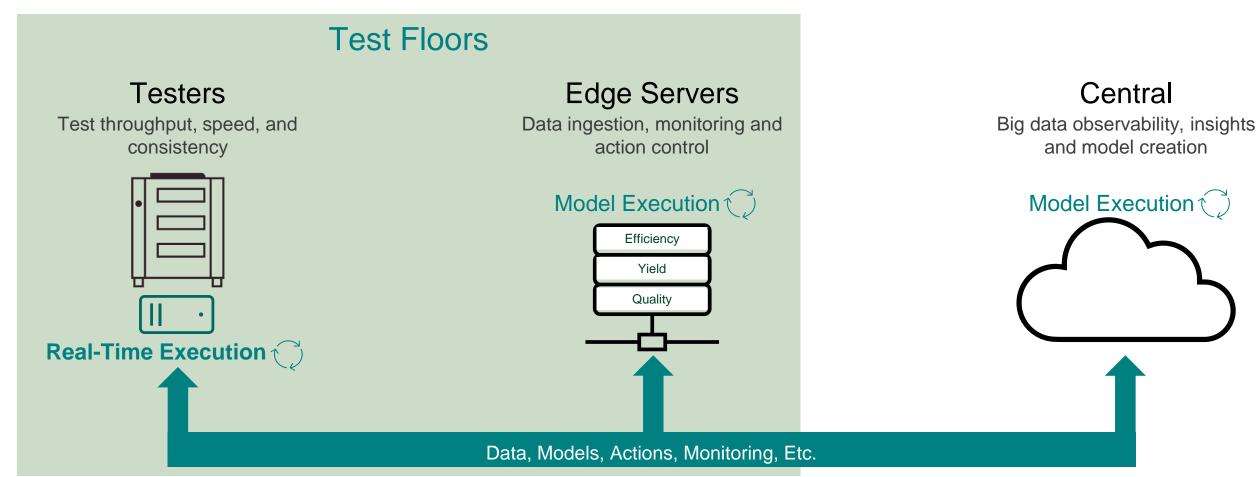
Edge, Nexus, & ACS

**TERADYNE** 

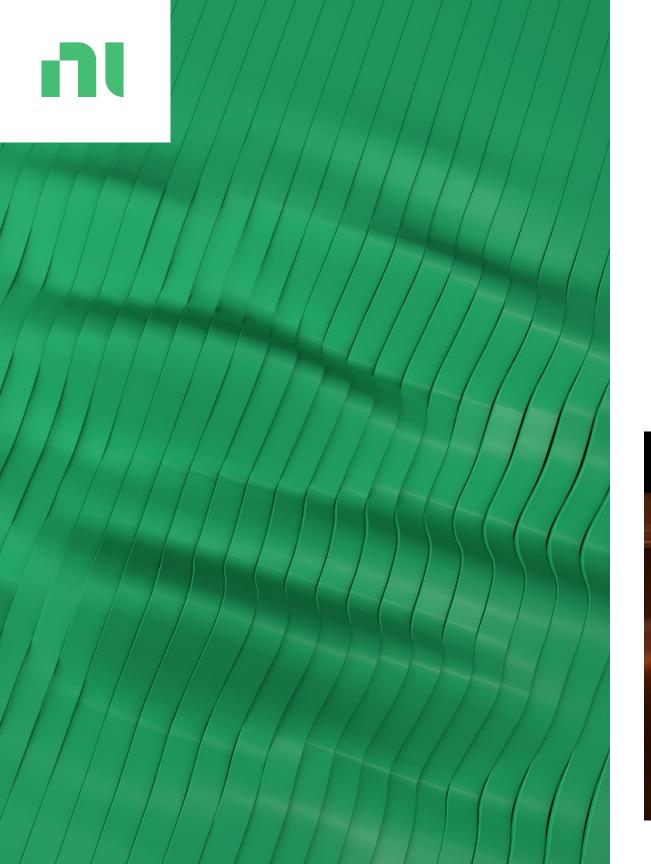
UltraEDGE & Archimedes



(standalone)







# Thank You!



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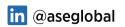




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